

FIG. 1

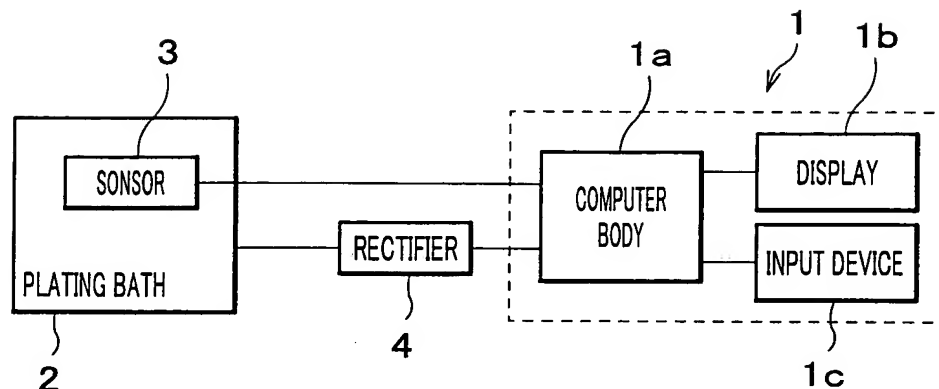


FIG. 2

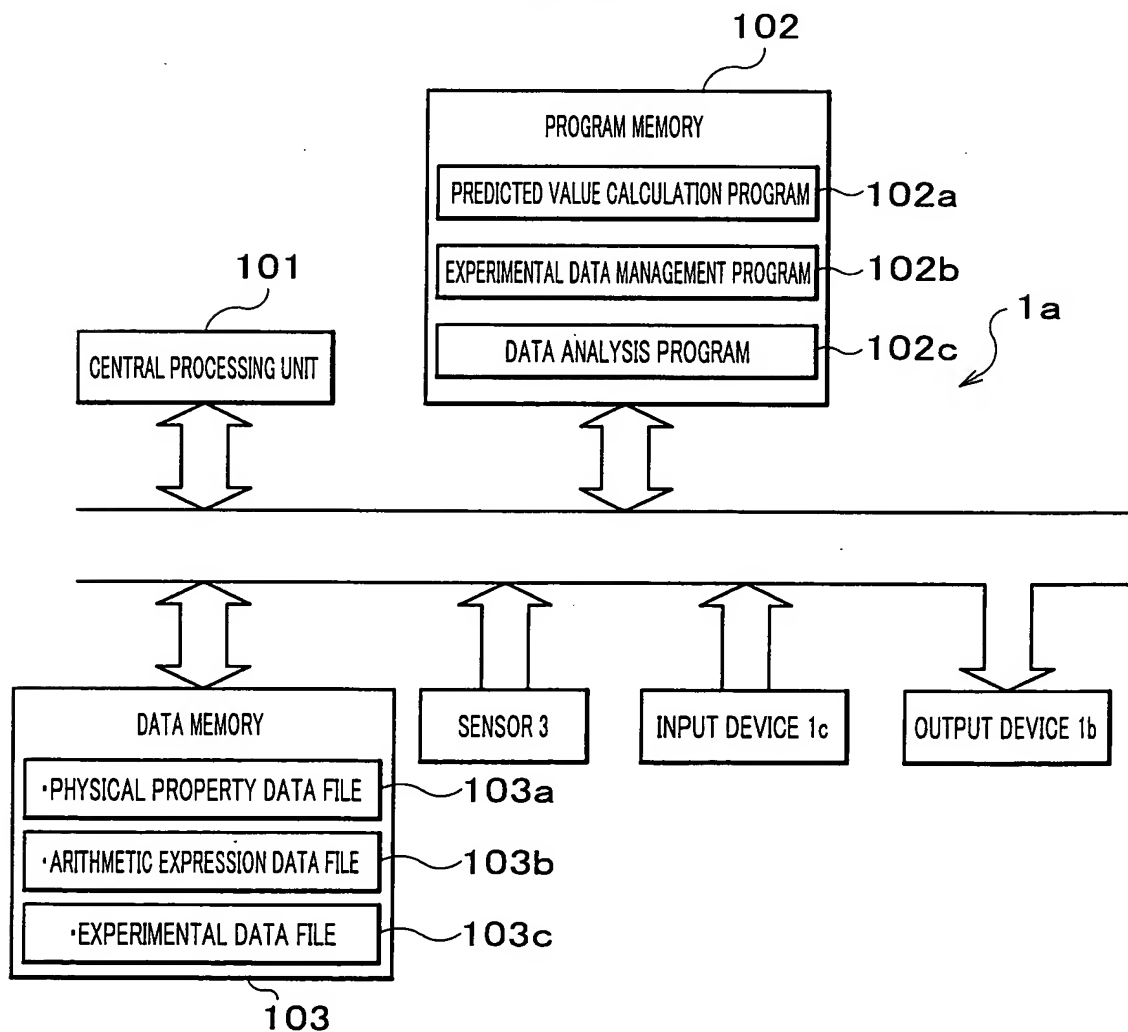


FIG.3

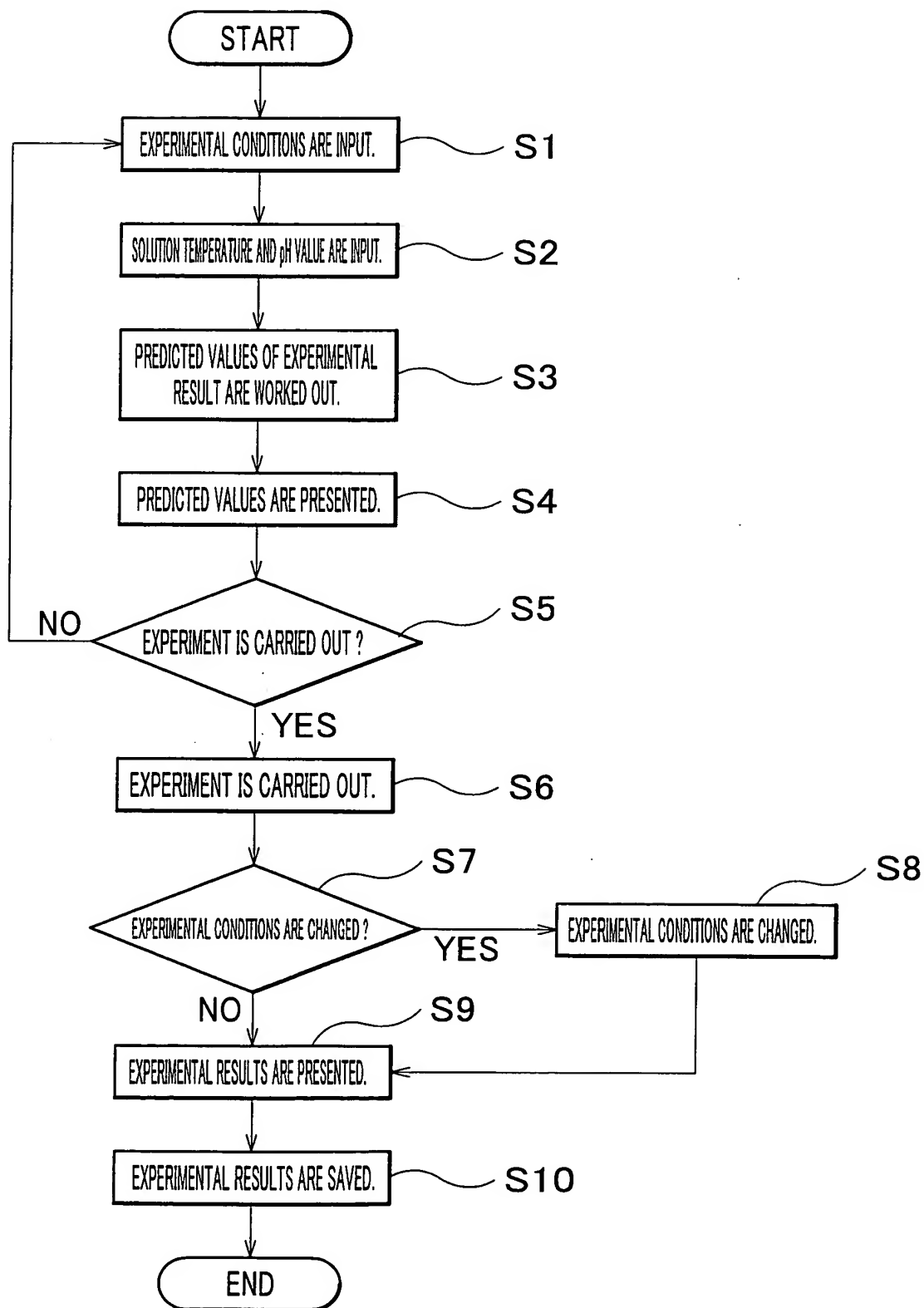


FIG. 4

5

SETTING VALUE INPUT FORM

5a ☐ NAME OF EXPERIMENT: Wafer Experiment No. 001

5c ☐ FILE NAME SAVED: WAFER-N001

5g ☐ NAME OF PLATING SOLUTION: Nickel-plated-Sulfamic Acid Solution

5j ☐ TYPE OF PLATING SOLUTION: Nickel, Ni

5h ☐ RECONFIGURATION OF PLATING SOLUTION

5b ☐ DATE: 10 November, 2000

5d ☐ NAME OF PERSON: YAMAMOTO, Wataru

5e ☐ RECORDING EXPERIMENT

5h CONDITIONS OF ITEMS TO BE PLATED

☐ NAME: Wafer Specimen

☐ MATERIAL: Si/Ti/Cu

☐ SURFACE AREA: 8.00Q mm²

☐ PRE-PLATING WEIGHT: 155.663

5u SOLUTION TEMPERATURE: 15 °C

5v pH VALUE: 5.4 ph

5f COMMENT

SHOW EXPERIMENTAL PREDICTION FORM

CANCEL

5i PLATING CONDITIONS

☐ SET TEMPERATURE: 50 °C

☐ MAXIMUM ELECTRIC CURRENT VALUE: 2.00Q A

☐ PLATING TIME: 60 s

☐ ADJUSTABLE ELECTRIC CURRENT WAVE SETTING ☒

5o 50 °C

5p 2.00Q A

5q 60 s

STAGE	ELECTRIC CURRENT TIMES	ELECTRIC CURRENT VALUE (A)	Δ
A	10	0.500	
B	10	1.000	
C	40	2.000	

5r

5t ELECTRIC CURRENT VALUE

INTEGRATED ELECTRIC CURRENT VALUE

5s PREDICTED ELECTRIC CURRENT SCHEDULE

FIG.5A

5g

Not Specified	▲
Copper Cu^{2+}	
Nickel Ni^{2+}	
Chrome Cr^{6+}	
Tin Sn^{2+}	
Gold Au^+	
Specified	▼

FIG.5B

5j

RECONFIGURATION OF PLATING SOLUTION	
NAME	Ni^{2+} (Nickel)
VALENCE	2
GRAM-EQUIVALENT WEIGHT	29.346
DENSITY(g/cm3)	8.85
ELECTROCHEMICAL EQUIVALENT(mg/coulomb)	0.3041

Press 'Yes' to enter the above data

Yes No

FIG.5C

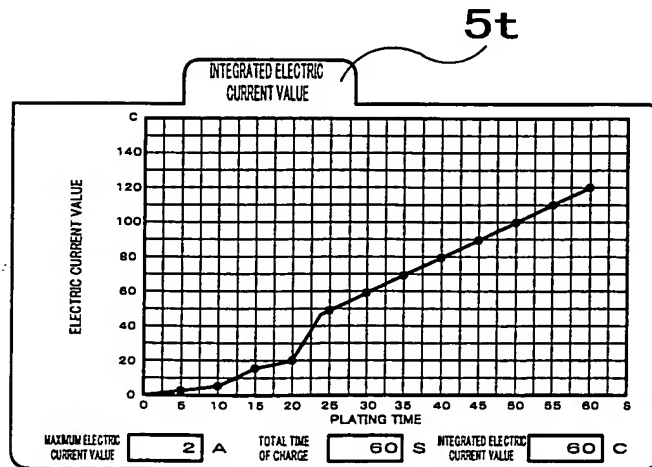


FIG. 6

6

EXPERIMENTAL PREDICTION FORM

NAME OF EXPERIMENT	Wafer Experiment No. 001	WAFER-NI001	YAMAMOTO, Watanu	10 November, 2000
NAME OF PLATING SOLUTION	Nickel-plated-Sulfamic Acid Solution		Wafer Specimen	SI/Ti/Cu

CURRENT CONDITIONS OF PLATING SOLUTION

SOLUTION TEMPERATURE
 °C

pH VALUE
 ph

START TEMPERATURE REGULATION

STOP TEMPERATURE REGULATION

☐ PREDICTED ELECTRIC CURRENT EFFICIENCY

CATHODIC ELECTRIC CURRENT EFFICIENCY
 %

UPDATE GRAPH

PREDICTED AVERAGE PLATING THICKNESS
 (as cathodic electric current efficiency is)

PREDICTED PLATING WEIGHT
 (as cathodic electric current efficiency is)

RETURN TO SETTING VALUE INPUT FORM

OK

CANCEL

6a

6b

FIG. 7

7c 7d 7e 7f 7g

EXPERIMENT FORM

NAME OF EXPERIMENT	Wafer Experiment No. 001	YAMAMOTO, Wataru	10 November, 2000
NAME OF PLATING SOLUTION	Nickel-plated-Sulfamic Acid Solution	NAME OF ITEM	Water Specimen
		MATERIAL OF ITEM	Si/Ti/Cu

7a

CURRENT ELECTRIC CURRENT VALUE

2.000 A

VOLTAGE VALUE

5.00 A

CURRENT DISCHARGING CURRENT VALUE

50.000 C

TEMPERATURE

50.0 °C

CURRENT pH VALUE

5.4 pH

PREDICTED CATHODIC ELECTRIC CURRENT EFFECT

94 %

PREDICTED CURRENT PLATING THICKNESS

1.55 μm

PREDICTED CURRENT PLATING HEIGHT

0.146 g

7b

PREDICTED AVERAGE PLATING THICKNESS (as cathodic electric current efficiency is 94%)

Plating Time (s)	Plating Thickness (μm)
0	0.0
5	0.5
10	1.0
15	1.5
20	2.0
25	2.5
30	2.5
35	2.5
40	2.5
45	2.5
50	2.5
55	2.5
60	2.5

7c

TEMPERATURE REGULATOR

pH GAUGE

7d

PLATING ELAPSED TIME

00' 00" 25.00

7e

SUSPEND EXPERIMENT

7f

STOP ELECTRIC CHARGE

7g

TO ELECTRIC CURRENT VALUE ALTERATION FORM

7a

RECONFIGURE

2.500 μm

FINAL AVERAGE PLATING THICKNESS

COLUMN FOR CURRENT REGARDING EXPERIMENT

7b

ERROR MESSAGE: OPERATING NORMALLY

FIG.8

8c
8d
8e
8f
8g
8g

EXPERIMENTAL RESULT ANALYSIS FORM

NAME OF EXPERIMENT	Wafer Experiment No. 001	WAFER-NI001	YAMAMOTO, Wataru	10 November, 2000
NAME OF PLATING SOLUTION	Nickel-plated-Sulfamic Acid Solution	NAME OF ITEM	Wafer Specimen	MATERIAL OF ITEM
SK/Ti/Cu				

8b

CHANGE IN ELECTRIC CURRENT VALUE

CHANGE IN VOLTAGE VALUE

CHANGE IN INTEGRATED ELECTRIC CURRENT VALUE

CHANGE IN SOLUTION TEMPERATURE

CHANGE IN pH VALUE

CHANGE IN PLATING THICKNESS

CHANGE IN PLATING HEIGHT

8a

CHANGE IN PLATING THICKNESS

Plating Time (S)	Plating Thickness (μm)
0	0.00
5	0.25
10	0.44
15	0.70
20	0.95
25	1.60
30	1.90
35	2.07
40	2.15
45	2.20
50	2.24
55	2.31
60	2.48

INPUT RESULT

PRE-PLATING WEIGHT 155.663 g

POST PLATING WEIGHT 155.798 g

DEPOSITED PLATING WEIGHT 0.135 g

OK

AVERAGE CATHODIC ELECTRIC CURRENT EFFICIENCY 93.2 %

FINAL AVERAGE PLATING THICKNESS 2.436 μm

PLATING TIME 25 S

ELECTRIC CURRENT VALUE 2.000 A

VOLTAGE VALUE 5.00 V

ACID/BASE/CURRENT 50.000 C

SOLUTION TEMPERATURE 50.0 °C

pH VALUE 5.4

PLATING THICKNESS 2.5 μm

PLATING WEIGHT 0.146 g

CALIBRATED IN 5 SECONDS

TO EXPERIMENTAL RESULT NUMERIC VALUE FORM

Q68543
EXPERIMENTAL MANAGEMENT APPARATUS AND
EXPERIMENTAL MANAGEMENT PROGRAM FOR
ELECTROPLATING
Filed: February 19, 2002
Darryl Mexic
202-293-7060
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FIG. 9

9

EXPERIMENTAL RESULT NUMERICAL VALUE FORM

NAME OF EXPERIMENT		Wafer Experiment No. 001		WAFER-NI001		YAMAMOTO, Wataru		10 November, 2000			
NAME OF PLATING SOLUTION		Nickel-plated-Sulfamic Acid Solution		NAME OF ITEM		Wafer Specimen		MATERIAL OF ITEM		Si/Ti/Cu	
PLATING TIMES	ELECTRIC CURRENT VALUE(A)	VOLUME VALUE(A)	PERCENTAGE CURRENT VALUE	SOLUTION TEMPERATURE(°C)	PH VALUE(A)	PLATING THICKNESS(μm)	PLATING WEIGHT(g)	Δ	▽		
0	XXXX	XXXX	XXXX	XXXX	XXXX	XXXX	XXXX	XXXX	XXXX		
1	XXXX	XXXX	XXXX	XXXX	XXXX	XXXX	XXXX	XXXX	XXXX		
2	XXXX	XXXX	XXXX	XXXX	XXXX	XXXX	XXXX	XXXX	XXXX		
3	XXXX	XXXX	XXXX	XXXX	XXXX	XXXX	XXXX	XXXX	XXXX		
4	XXXX	XXXX	XXXX	XXXX	XXXX	XXXX	XXXX	XXXX	XXXX		
5	XXXX	XXXX	XXXX	XXXX	XXXX	XXXX	XXXX	XXXX	XXXX		
6	XXXX	XXXX	XXXX	XXXX	XXXX	XXXX	XXXX	XXXX	XXXX		
7	XXXX	XXXX	XXXX	XXXX	XXXX	XXXX	XXXX	XXXX	XXXX		
8	XXXX	XXXX	XXXX	XXXX	XXXX	XXXX	XXXX	XXXX	XXXX		
9	XXXX	XXXX	XXXX	XXXX	XXXX	XXXX	XXXX	XXXX	XXXX		
10	XXXX	XXXX	XXXX	XXXX	XXXX	XXXX	XXXX	XXXX	XXXX		
11	XXXX	XXXX	XXXX	XXXX	XXXX	XXXX	XXXX	XXXX	XXXX		
12	XXXX	XXXX	XXXX	XXXX	XXXX	XXXX	XXXX	XXXX	XXXX		
13	XXXX	XXXX	XXXX	XXXX	XXXX	XXXX	XXXX	XXXX	XXXX		
14	XXXX	XXXX	XXXX	XXXX	XXXX	XXXX	XXXX	XXXX	XXXX		
15	XXXX	XXXX	XXXX	XXXX	XXXX	XXXX	XXXX	XXXX	XXXX		
16	XXXX	XXXX	XXXX	XXXX	XXXX	XXXX	XXXX	XXXX	XXXX		
17	XXXX	XXXX	XXXX	XXXX	XXXX	XXXX	XXXX	XXXX	XXXX		
18	XXXX	XXXX	XXXX	XXXX	XXXX	XXXX	XXXX	XXXX	XXXX		
19	XXXX	XXXX	XXXX	XXXX	XXXX	XXXX	XXXX	XXXX	XXXX		
20	XXXX	XXXX	XXXX	XXXX	XXXX	XXXX	XXXX	XXXX	XXXX		
21	XXXX	XXXX	XXXX	XXXX	XXXX	XXXX	XXXX	XXXX	XXXX		
22	XXXX	XXXX	XXXX	XXXX	XXXX	XXXX	XXXX	XXXX	XXXX		
23	XXXX	XXXX	XXXX	XXXX	XXXX	XXXX	XXXX	XXXX	XXXX		
24	XXXX	XXXX	XXXX	XXXX	XXXX	XXXX	XXXX	XXXX	XXXX		
25	XXXX	XXXX	XXXX	XXXX	XXXX	XXXX	XXXX	XXXX	XXXX		
26	XXXX	XXXX	XXXX	XXXX	XXXX	XXXX	XXXX	XXXX	XXXX		
27	XXXX	XXXX	XXXX	XXXX	XXXX	XXXX	XXXX	XXXX	XXXX		
28	XXXX	XXXX	XXXX	XXXX	XXXX	XXXX	XXXX	XXXX	XXXX		
29	XXXX	XXXX	XXXX	XXXX	XXXX	XXXX	XXXX	XXXX	XXXX		
30	XXXX	XXXX	XXXX	XXXX	XXXX	XXXX	XXXX	XXXX	XXXX		
31	XXXX	XXXX	XXXX	XXXX	XXXX	XXXX	XXXX	XXXX	XXXX		

SAVE IN CSV FORMAT